

MUX-16/MUX-28

FEATURES

- JFET Switches Rather Than CMOS
- Highly Resistant To Static Discharge Damage
- No SCR Latch-up Problems
- Low "ON" Resistance — 290Ω Typical
- Low Leakage Current
- Digital Inputs Compatible With TTL and CMOS
- Break-Before-Make Action
- 125° C Temperature-Tested Dice Available
- Overvoltage Protected
- Supply Loss Protection
- MUX-16 Pin Compatible With DG506, HI-506A, AD7506
- MUX-28 Pin Compatible With DG507, HI-507A, AD7507
- Available In Die Form

ORDERING INFORMATION †

| 25°C RESISTANCE | PACKAGE | | | OPERATING TEMPERATURE RANGE |
|--------------------|------------------|-------------------|-------------------|-----------------------------------|
| | CERDIP 28-PIN | LCC 28-CONTACT | PLASTIC 28-PIN | |
| 290Ω | MUX16AT* | — | — | MIL |
| 290Ω | MUX16ET | — | — | IND |
| 400Ω | MUX16BT* | MUX16BTC/883 | — | MIL |
| 400Ω | MUX16FT | — | MUX16FP | XIND |
| 400Ω | — | — | MUX16FPC | XIND |
| 290Ω | MUX28AT* | — | — | MIL |
| 290Ω | MUX28ET | — | — | IND |
| 400Ω | MUX28BT* | MUX28BTC/883 | — | MIL |
| 400Ω | MUX28FT | — | MUX28FP | XIND |
| 400Ω | — | — | MUX28FPC | XIND |

* For devices processed in total compliance to MIL-STD-883, add /883 after part number. Consult factory for 883 data sheet.

† Burn-in is available on commercial and industrial temperature range parts in CerDIP, plastic DIP, and TO-can packages.

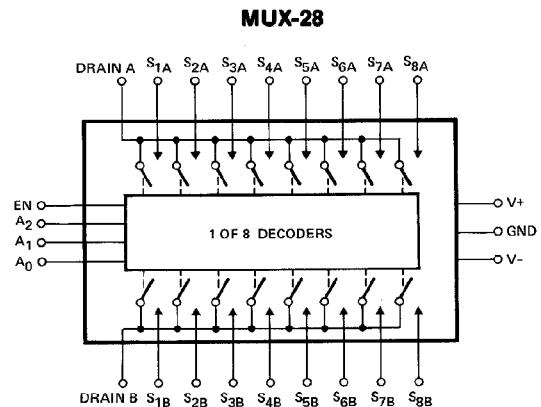
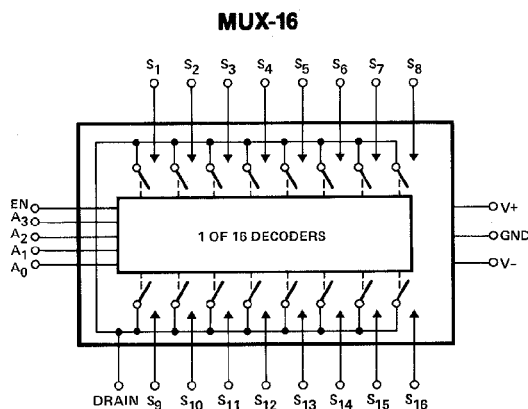
GENERAL DESCRIPTION

The MUX-16 is a monolithic 16-channel analog multiplexer which connects a single output to 1 of the 16 analog inputs depending upon the state of a 4-bit binary address. Disconnection of the output is provided by a logical "0" at the ENABLE input, thereby providing a package selection function.

The MUX-28 is a monolithic 8-channel differential analog multiplexer configured in a double pole, 8-position (plus OFF) electronic switch array. A 3-bit binary input address connects a pair of independent analog inputs from each 8-channel input section to the corresponding pair of independent analog outputs. Disconnection of both inputs is provided by a logical "0" at the ENABLE input, thereby offering a package select function.

Fabricated with Precision Monolithics' high performance Bipolar-JFET technology, these devices offer low, constant "ON" resistance. Performance advantages include low leakage currents and fast settling time with low crosstalk to satisfy a wide variety of applications. These multiplexers do not suffer from latch-up or static discharge blow-out problems associated with similar CMOS parts. The digital inputs are designed to operate from both TTL and CMOS levels while always providing a definite break-before-make action without the need for external pull-up resistors. For single 8-channel and dual 4-channel models, refer to the MUX-08/MUX-24 data sheet.

FUNCTIONAL DIAGRAMS



REV. A

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MUX-16/MUX-28

PIN CONNECTIONS & TRUTH TABLES

MUX-16

28-PIN PLASTIC DIP (P-Suffix)
28-PIN CERDIP (T-Suffix)

MUX-28

MUX-16BTC/883
LCC (TC-Suffix)
PLCC (PC-Suffix)

MUX-16

| "ON" | | | | | "ON" | | | | | | |
|----------------|----------------|----------------|----------------|----|---------|----------------|----------------|----------------|----------------|----|---------|
| A ₃ | A ₂ | A ₁ | A ₀ | EN | CHANNEL | A ₃ | A ₂ | A ₁ | A ₀ | EN | CHANNEL |
| X | X | X | X | L | NONE | H | L | L | L | H | 9 |
| L | L | L | L | H | 1 | H | L | L | H | H | 10 |
| L | L | L | H | H | 2 | H | L | H | L | H | 11 |
| L | L | H | L | H | 3 | H | L | H | H | H | 12 |
| L | L | H | H | H | 4 | H | H | L | L | H | 13 |
| L | H | L | L | H | 5 | H | H | L | H | H | 14 |
| L | H | L | H | H | 6 | H | H | H | L | H | 15 |
| L | H | H | L | H | 7 | H | H | H | H | H | 16 |
| L | H | H | H | H | 8 | | | | | | |

MUX-28

| "ON" | | | | |
|----------------|----------------|----------------|----|--------------|
| A ₂ | A ₁ | A ₀ | EN | CHANNEL PAIR |
| X | X | X | L | NONE |
| L | L | L | H | 1 |
| L | L | H | H | 2 |
| L | H | L | H | 3 |
| L | H | H | H | 4 |
| H | L | L | H | 5 |
| H | L | H | H | 6 |
| H | H | L | H | 7 |
| H | H | H | H | 8 |

ABSOLUTE MAXIMUM RATINGS (Note 1)

Operating Temperature Range,
 MUX-16/28-AT, BT, BTC -55°C to +125°C
 MUX-16/28-ET -25°C to +85°C
 MUX-16/28-FP, FPC, FT -40°C to +85°C
 Junction Temperature (T_J) -65°C to +150°C
 Storage Temperature Range -65°C to +150°C
 Lead Temperature (Soldering, 60 sec) 300°C
 Maximum Junction Temperature 150°C
 V₊ Supply to V₋ Supply 36V
 Logic Input Voltage (V₋ or -4V) to V₊ Supply
 Analog Input Voltage V₋ Supply -20V to V₊ Supply +20V

Maximum Current Through Any Pin 25mA

| PACKAGE TYPE | e _{JA} (Note 2) | e _{JC} | UNITS |
|-------------------------|--------------------------|-----------------|-------|
| 28-Pin Hermetic DIP (T) | 55 | 15 | °C/W |
| 28-Pin Plastic DIP (P) | 56 | 30 | °C/W |
| 28-Contact LCC (TC) | 86 | 35 | °C/W |
| 28-Contact PLCC (PC) | 70 | 33 | °C/W |

NOTES:

- Ratings apply to both DICE and packaged parts, unless otherwise noted.
- e_{JA} is specified for worst case mounting conditions, i.e., e_{JA} is specified for device in socket for CerDIP, P-DIP, and LCC packages; e_{JA} is specified for device soldered to printed circuit board for PLCC package.

ELECTRICAL CHARACTERISTICS at V_S = ±15V and T_A = 25°C, unless otherwise noted.

| PARAMETER | SYMBOL | CONDITIONS | MUX-16A/E MUX-28A/E | | | MUX-16B/F MUX-28B/F | | | UNITS | |
|--|---|--|------------------------|------|-----|------------------------|------|-----|-------|----|
| | | | MIN | TYP | MAX | MIN | TYP | MAX | | |
| "ON" Resistance | R _{ON} | V _S ≤ 10V, I _S ≤ 200μA | — | 290 | 380 | — | 400 | 580 | Ω | |
| ΔR _{ON} With Applied Voltage | ΔR _{ON} | -10V ≤ V _S ≤ 10V, I _S = 200μA | — | 1.5 | 5 | — | 1.5 | 5 | % | |
| R _{ON} Match Between Switches | R _{ON} Match | V _S = 0V, I _S = 200μA | — | 7 | 15 | — | 9 | 20 | % | |
| Analog Voltage Range | V _A | {Note 6} | +10 | +11 | — | +10 | +11 | — | V | |
| Source Current (Switch "OFF") | I _S (OFF) | V _S = 10V, V _D = -10V (Note 1) | — | 0.01 | 1 | — | 0.01 | 2 | nA | |
| Drain Current (Switch "OFF") | I _D (OFF) | V _S = 10V, V _D = -10V (Note 1) | MUX-16 | — | 0.2 | 1 | — | 0.2 | 2 | nA |
| | | | MUX-28 | — | 0.1 | 1 | — | 0.1 | 2 | nA |
| Leakage Current (Switch "ON") | I _D (ON) +I _S (ON) | V _D = 10V (Note 1) | MUX-16 | — | 0.2 | 1 | — | 0.2 | 2 | nA |
| | | | MUX-28 | — | 0.1 | 1 | — | 0.1 | 2 | nA |
| Digital Input Current | I _{IN} | V _{IN} = 0.4V to 15V | — | 1 | 10 | — | 1 | 10 | μA | |

MUX-16/MUX-28

ELECTRICAL CHARACTERISTICS at $V_S = \pm 15V$ and $T_A = +25^\circ C$, unless otherwise noted. *Continued*

| PARAMETER | SYMBOL | CONDITIONS | MUX-16A/E MUX-28A/E | | | MUX-16B/F MUX-28B/F | | | UNITS | |
|---|---------------|---|------------------------|------|------|------------------------|------|------|---------|---------|
| | | | MIN | TYP | MAX | MIN | TYP | MAX | | |
| Digital "0" Enable Current | $I_{INL(EN)}$ | $V_{EN} = 0.4V$ | – | 4 | 10 | – | 4 | 10 | μA | |
| Digital Input Capacitance | C_{DIG} | | – | 3 | – | – | 3 | – | pF | |
| Switching Time (t_{TRAN}) | t_{PHL} | (Notes 2,5) Figure 1 (Test Circuits) | – | 1.4 | 2.0 | – | 1.8 | 2.5 | μs | |
| | t_{PLH} | | – | 1.2 | 1.8 | – | 1.6 | 2.2 | | |
| Output Settling Time | t_s | 10V Step to 0.10% | – | 2.6 | – | – | 2.7 | – | μs | |
| | | 10V Step to 0.05% | – | 3.2 | – | – | 3.4 | – | | |
| | | 10V Step to 0.02% | – | 4.0 | – | – | 7.2 | – | | |
| Break-Before-Make Delay | t_{OPEN} | Figure 3 | – | 0.7 | – | – | 1 | – | μs | |
| Enable Delay "ON" | $t_{ON(EN)}$ | (Note 5) Figure 2 (Test Circuits) | – | 1 | 2 | – | 1.2 | 2.5 | μs | |
| Enable Delay "OFF" | $t_{OFF(EN)}$ | (Note 5) Figure 2 (Test Circuits) | MUX-16 | – | 0.25 | 0.5 | – | 0.25 | 0.5 | μs |
| | | | MUX-28 | – | 0.25 | 0.5 | – | 0.25 | 0.6 | |
| "OFF" Isolation | ISO_{OFF} | (Note 4) Figure 4 (Test Circuits) | – | 66 | – | – | 66 | – | dB | |
| Crosstalk | CT | (Note 3) Figure 5 (Test Circuits) | – | 75 | – | – | 75 | – | dB | |
| Source Capacitance | $C_{S(OFF)}$ | Switch "OFF," $V_S = 0V, V_D = 0V$ | – | 2.5 | – | – | 2.5 | – | pF | |
| Drain Capacitance | $C_{D(OFF)}$ | Switch "OFF," $V_S = 0V, V_D = 0V$ | MUX-16 | – | 13 | – | – | 13 | – | pF |
| | | | MUX-28 | – | 8 | – | – | 8 | – | |
| Input to Output Capacitance | $C_{DS(OFF)}$ | (Note 4) | – | 0.15 | – | – | 0.15 | – | pF | |
| Positive Supply Current (All Digital Inputs Logic "0" or "1") | I_+ | $V_+ = 15V$ | MUX-16 | – | 15 | 19 | – | 9 | 19 | mA |
| | | | MUX-28 | – | 15 | 19 | – | 8 | 19 | |
| | | $V_+ = 5V$ | MUX-16 | – | 12 | – | – | 8 | – | |
| | | | MUX-28 | – | 12 | – | – | 7 | – | |
| Negative Supply Current (All Digital Inputs Logic "0" or "1") | I_- | $V_- = -15V$ | MUX-16 | – | 5 | 7 | – | 3.5 | 7 | mA |
| | | | MUX-28 | – | 5 | 7 | – | 3 | 7 | |
| | | $V_- = -5V$ | MUX-16 | – | 4 | – | – | 3 | – | |
| | | | MUX-28 | – | 4 | – | – | 2.5 | – | |

NOTES:

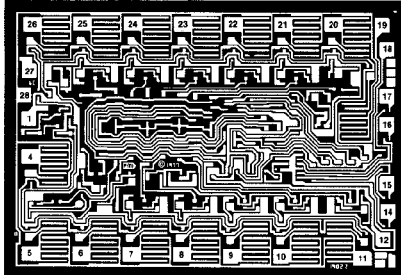
- Conditions applied to leakage tests insure worst case leakages.
- $R_L = 10M\Omega, C_L = 10pF$.
- Crosstalk is measured by driving channel 8 (8B*) with channel 7 (7B*) ON.
 $R_L = 1M\Omega, C_L = 10pF, V_S = 5V$ RMS, $f = 500kHz$.
- "OFF" isolation is measured by driving channel 8 (8B) with ALL channels OFF.
 $R_L = 1k\Omega, C_L = 10pF, V_S = 5V$ RMS, $f = 500kHz$. C_{DS} is computed from the OFF isolation measurement.
- Sample tested.
- Guaranteed by leakage current and R_{ON} tests.

ELECTRICAL CHARACTERISTICS at $V_S = \pm 15V, -55^\circ C \leq T_A \leq +125^\circ C$ for MUX-16AT/BT/BTC and MUX-28AT/BT/BTC; $-25^\circ C \leq T_A \leq +85^\circ C$ for MUX-16ET and MUX-28ET; $-40^\circ C \leq T_A \leq +85^\circ C$ for MUX-16 FT/FP/FPC and MUX-28FT/FP/FPC, unless otherwise noted.

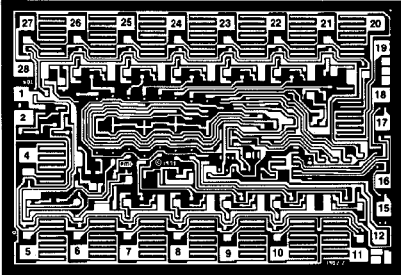
| PARAMETER | SYMBOL | CONDITIONS | MUX-16A/E MUX-28A/E | | | MUX-16B/F MUX-28B/F | | | UNITS |
|--------------------------------------|-----------------|--|------------------------|------------|-----|------------------------|------------|-----|----------|
| | | | MIN | TYP | MAX | MIN | TYP | MAX | |
| "ON" Resistance | R_{ON} | $V_S \leq 10, I_S \leq 200\mu A$ | – | – | 500 | – | – | 800 | Ω |
| ΔR_{ON} With Applied Voltage | ΔR_{ON} | $-10V \leq V_S \leq 10V, I_S = 200\mu A$ | – | 2 | – | – | 5.5 | – | % |
| R_{ON} Match Between Switches | R_{ON} Match | $V_S = 0V, I_S = 200\mu A$ | – | 10 | – | – | 15 | – | % |
| Analog Voltage Range | V_A | (Note 6) | +10 –10 | +11 –15 | – | +10 –10 | +11 –15 | – | V |
| Source Current (Switch "OFF") | $I_{S(OFF)}$ | $V_S = 10V, V_D = -10V$ (Note 1) | – | – | 25 | – | – | 50 | nA |
| Drain Current (Switch "OFF") | $I_{D(OFF)}$ | $V_S = 10V, V_D = -10V$ (Note 1) | – | – | 75 | – | – | 250 | nA |
| Leakage Current (Switch "ON") | $I_{D(ON)}$ | $V_D = 10V$ (Note 1) | – | – | 75 | – | – | 250 | nA |
| | $+I_{S(ON)}$ | | | | | | | | |
| Digital "1" Input Voltage | V_{INH} | (Note 6) | 2 | – | – | 2 | – | – | V |
| Digital "0" Input Voltage | V_{INL} | (Note 6) | – | – | 0.7 | – | – | 0.7 | V |
| Digital Input Current | I_{IN} | $V_{IN} = 0.4V$ to 15V | – | – | 20 | – | – | 20 | μA |
| Digital "0" Enable Current | $I_{INL(EN)}$ | $V_{EN} = 0.4V$ | – | – | 20 | – | – | 20 | μA |
| Positive Supply Current | I_+ | All Digital Inputs Logic "0" or "1" | – | – | 24 | – | – | 24 | mA |
| Negative Supply Current | I_- | All Digital Inputs Logic "0" or "1" | – | – | 8.2 | – | – | 8.2 | mA |

MUX-16/MUX-28

DICE CHARACTERISTICS (125°C TESTED DICE AVAILABLE)



MUX-16



MUX-28

**DIE SIZE 0.110 × 0.076 inch, 8360 sq. mils
(2.794 × 1.930 mm, 5392 sq. mm)**

1. POSITIVE SUPPLY
4. SOURCE 16 (S16)
5. SOURCE 15 (S15)
6. SOURCE 14 (S14)
7. SOURCE 13 (S13)
8. SOURCE 12 (S12)
9. SOURCE 11 (S11)
10. SOURCE 10 (S10)
11. SOURCE 9 (S9)
12. GROUND
14. ADDRESS BIT 3 (A3)
15. ADDRESS BIT 2 (A2)
16. ADDRESS BIT 1 (A1)
17. ADDRESS BIT 0 (A0)
18. ENABLE
19. SOURCE 1 (S1)
20. SOURCE 2 (S2)
21. SOURCE 3 (S3)
22. SOURCE 4 (S4)
23. SOURCE 5 (S5)
24. SOURCE 6 (S6)
25. SOURCE 7 (S7)
26. SOURCE 8 (S8)
27. NEGATIVE SUPPLY (SUBSTRATE)
28. DRAIN

1. POSITIVE SUPPLY
2. DRAIN B
4. SOURCE 8 (S8B)
5. SOURCE 7 (S7B)
6. SOURCE 6 (S6B)
7. SOURCE 5 (S5B)
8. SOURCE 4 (S4B)
9. SOURCE 3 (S3B)
10. SOURCE 2 (S2B)
11. SOURCE 1 (S1B)
12. GROUND
15. ADDRESS BIT 2 (A2)
16. ADDRESS BIT 1 (A1)
17. ADDRESS BIT 0 (A0)
18. ENABLE
19. SOURCE 1 (S1A)
20. SOURCE 2 (S2A)
21. SOURCE 3 (S3A)
22. SOURCE 4 (S4A)
23. SOURCE 5 (S5A)
24. SOURCE 6 (S6A)
25. SOURCE 7 (S7A)
26. SOURCE 8 (S8A)
27. NEGATIVE SUPPLY (SUBSTRATE)
28. DRAIN A

WAFER TEST LIMITS at $V_+ = 15V$, $V_- = -15V$, $T_A = 25^\circ C$ for MUX-16/28 N and G, $T_A = 125^\circ C$ for MUX-16/28 NT and GT, unless otherwise noted.

| PARAMETER | SYMBOL | CONDITIONS | MUX-16/ MUX-28NT | MUX-16/ MUX-28N | MUX-16/ MUX-28GT | MUX-16/ MUX-28G | UNITS |
|---|---------------|----------------------------------|---------------------|--------------------|---------------------|--------------------|--------------|
| | | | LIMIT | LIMIT | LIMIT | LIMIT | |
| "ON" Resistance | R_{ON} | $V_S = 0V$, $I_S = 200\mu A$ | 540 | 380 | 800 | 580 | Ω MAX |
| Digital "1" Input Voltage | V_{INH} | | 2 | 2 | 2 | 2 | V MIN |
| Digital "0" Input Voltage | V_{INL} | | 0.8 | 0.8 | 0.8 | 0.8 | V MAX |
| Digital "0" Input Current | I_{INL} | $V_{IN} = 0.4V$ | 20 | 10 | 20 | 10 | μA MAX |
| Digital "0" Enable Current | $I_{INL(EN)}$ | $V_{EN} = 0.4V$ | 20 | 10 | 20 | 10 | μA MAX |
| Positive Supply Current (All Digital Inputs Logic "0") | I_+ | | 24 | 19 | 24 | 19 | mA MAX |
| Negative Supply Current (All Digital Inputs Logic "0") | I_- | | 8.2 | 7 | 8.2 | 7 | mA MAX |
| Analog Input Range | V_A | (Note 2) | ± 10 | ± 10 | ± 10 | ± 10 | V MIN |

NOTE:

Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

TYPICAL ELECTRICAL CHARACTERISTICS at $V_+ = 15V$, $V_- = -15V$ and $T_A = 25^\circ C$ for MUX-16/28 N and G, $T_A = 125^\circ C$ for MUX-16/28 NT and GT, unless otherwise noted.

| PARAMETER | SYMBOL | CONDITIONS | MUX-16/ MUX-28NT | MUX-16/ MUX-28N | MUX-16/ MUX-28GT | MUX-16/ MUX-28G | UNITS |
|--------------------------------------|-----------------|---|---------------------|--------------------|---------------------|--------------------|---------|
| | | | TYPICAL | TYPICAL | TYPICAL | TYPICAL | |
| Switching Time (t_{TRAN}) | t_{PHL} | (Note 1) Figure 1 | 2 | 1 | 2.6 | 1.5 | μS |
| | t_{PLH} | | 1.8 | 0.9 | 2.4 | 1.4 | |
| Output Settling Time | t_S | 10V Step to 0.1% (Note 1) | 2.5 | 1.5 | 2.9 | 1.9 | μS |
| Break-Before-Make Delay | t_{OPEN} | (Note 1) Figure 3 (Test Circuits) | 0.8 | 0.8 | 1 | 1 | μS |
| Crosstalk | CT | (Note 1) Figure 5 (Test Circuits) | 70 | 70 | 70 | 70 | dB |
| ΔR_{ON} With Applied Voltage | ΔR_{ON} | $-10V \leq V_S \leq 10V$, $I_S = 200\mu A$ | 1.5 | 1.5 | 1.5 | 1.5 | % |
| Leakage Current (Switch "ON") | $I_{D(ON)}$ | $V_D = 10V$ (Note 1) | 20 | 0.2 | 20 | 0.2 | nA |
| Analog Input Range | V_A | (Note 2) | +11 | +11 | +11 | +11 | V |
| | | | -15 | -15 | -15 | -15 | |

NOTES:

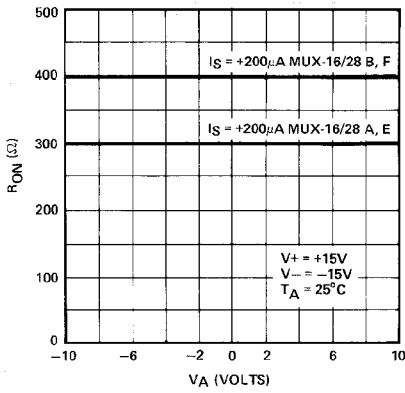
1. The data shown is extrapolated from measurements made on the packaged devices.

2. Guaranteed by R_{ON} and leakage current tests.

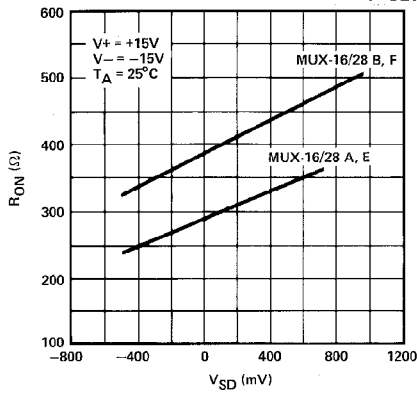
MUX-16/MUX-28

TYPICAL PERFORMANCE CHARACTERISTICS (apply to all grades, unless otherwise noted.)

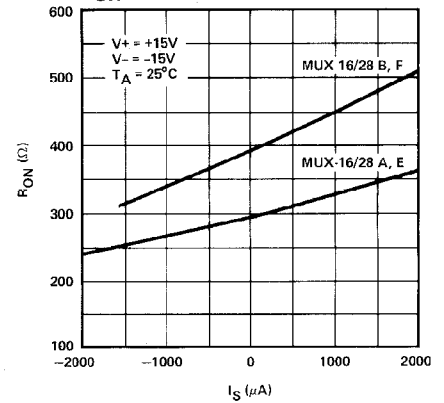
"ON" RESISTANCE (R_{ON}) vs ANALOG VOLTAGE (V_A)



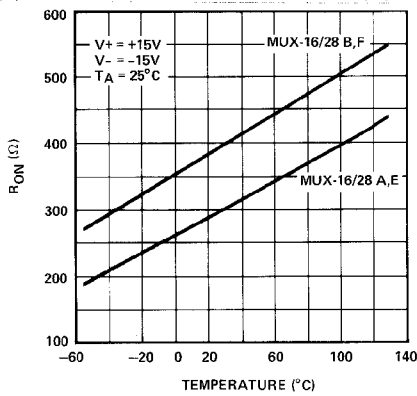
R_{ON} vs SWITCH VOLTAGE (V_{SD})



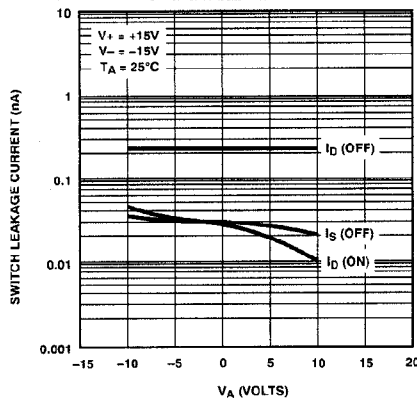
R_{ON} vs SWITCH CURRENT (I_S)



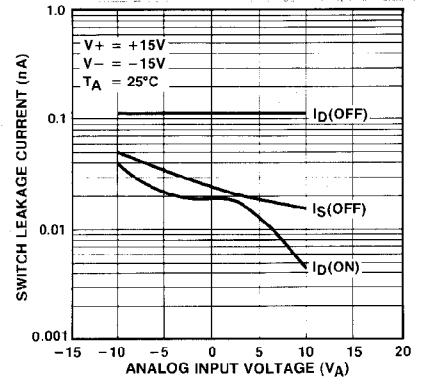
R_{ON} vs TEMPERATURE (T)



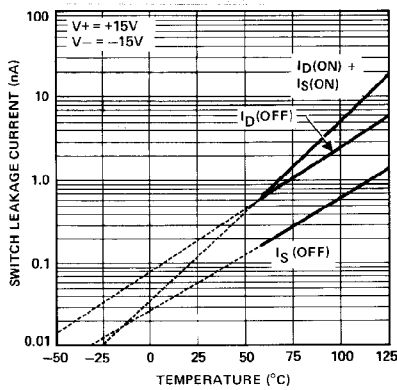
MUX-16 SWITCH LEAKAGE CURRENTS vs ANALOG INPUT VOLTAGE (V_A)



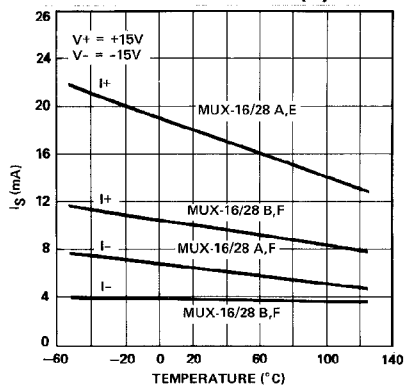
MUX-28 SWITCH LEAKAGE CURRENTS vs ANALOG INPUT VOLTAGE (V_A)



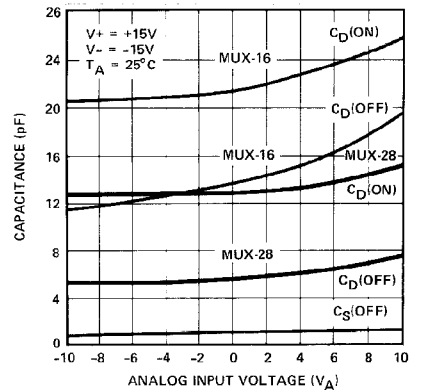
SWITCH LEAKAGE CURRENTS vs TEMPERATURE



SUPPLY CURRENTS vs TEMPERATURE (T)



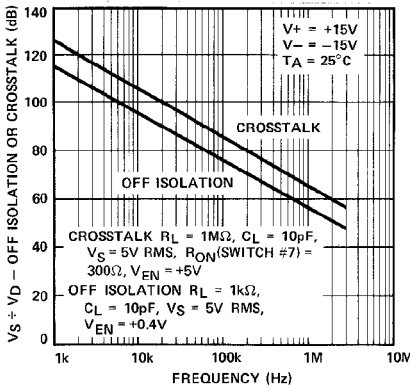
SWITCH CAPACITANCES vs ANALOG INPUT VOLTAGE (V_A)



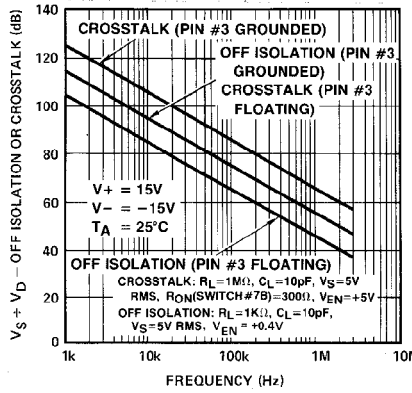
MUX-16/MUX-28

TYPICAL PERFORMANCE CHARACTERISTICS (apply to all grades, unless otherwise noted.)

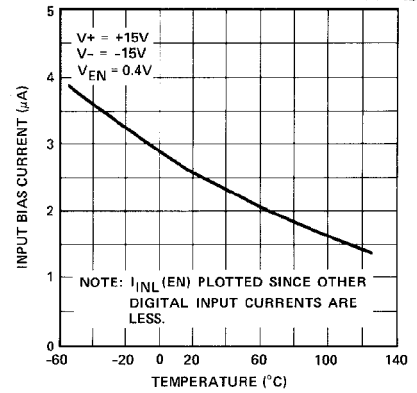
**MUX-16
OFF PERFORMANCE OF
CHANNEL 8**



**MUX-28
OFF PERFORMANCE OF
CHANNEL 8**

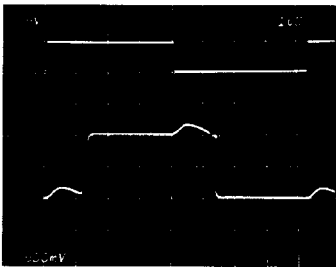


DIGITAL INPUT BIAS CURRENTS vs TEMPERATURE (T)



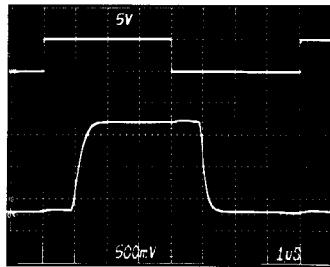
MUX-16 DYNAMIC CHARACTERISTIC CURVES

SMALL-SIGNAL SWITCHING



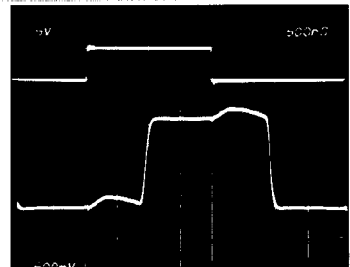
RL = 1MΩ, CL = 10pF, V1 = -500mV, V16 = +500mV

SMALL-SIGNAL SWITCHING WITH FILTERING



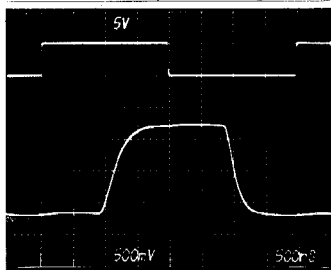
RL = 1MΩ, CL = 500pF, V1 = -500mV, V16 = +500mV

SMALL-SIGNAL SWITCHING WITH 2μs SAMPLE TIME



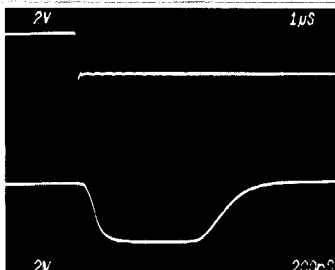
RL = 1MΩ, CL = 10pF, V1 = -700mV, V16 = +700mV

SMALL-SIGNAL SWITCHING WITH FILTERING AND 2μs SAMPLE TIME



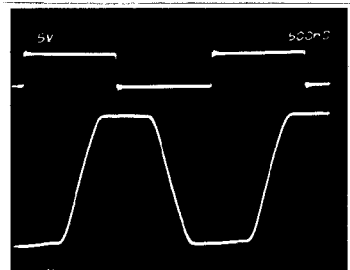
RL = 1MΩ, CL = 500pF, V1 = -700mV, V16 = +700mV

BREAK-BEFORE-MAKE SWITCHING



RL = 1kΩ, CL = 10pF, V1 = V16 = +10V

LARGE-SIGNAL SWITCHING



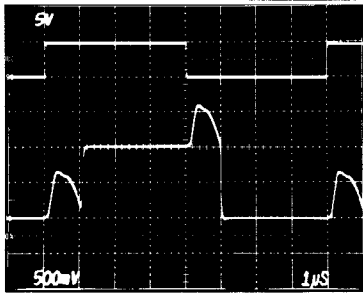
RL = 1MΩ, CL = 10pF, V1 = -10V, V16 = +10V

NOTE:

Top Waveforms: Digital Input 5V/Div
Bottom Waveforms: Multiplexer Output (V_D)

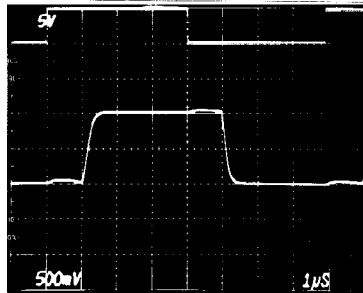
MUX-28 DYNAMIC CHARACTERISTIC CURVES

SMALL-SIGNAL SWITCHING



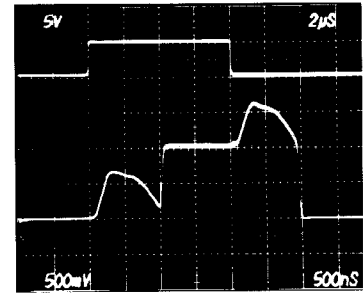
$R_L = 1M\Omega, C_L = 10pF, V_1 = -500mV, V_8 = +500mV$

SMALL-SIGNAL SWITCHING WITH FILTERING



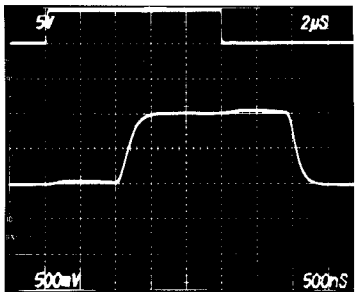
$R_L = 1M\Omega, C_L = 500pF, V_1 = -500mV, V_8 = +500mV$

SMALL-SIGNAL SWITCHING WITH 2µs SAMPLE TIME



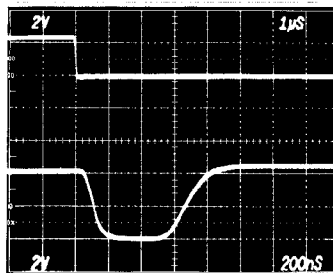
$R_L = 1M\Omega, C_L = 10pF, V_1 = -700mV, V_8 = +700mV$

SMALL-SIGNAL SWITCHING WITH FILTERING AND 2.5µs SAMPLE TIME



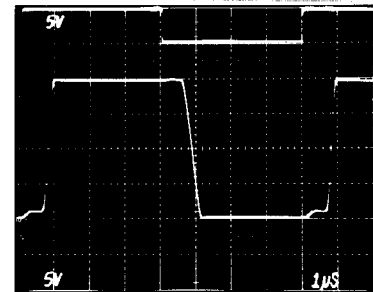
$R_L = 1M\Omega, C_L = 500pF, V_1 = -700mV, V_8 = +700mV$

BREAK-BEFORE-MAKE SWITCHING



$R_L = 1K\Omega, C_L = 10pF, V_1 = V_8 = +10V$

LARGE-SIGNAL SWITCHING



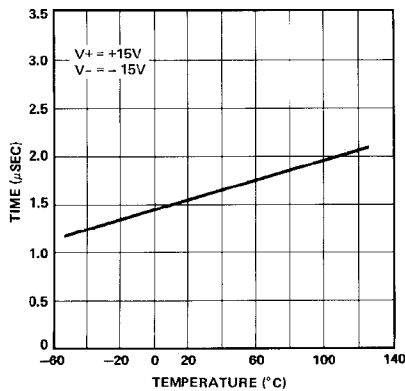
$R_L = 1M\Omega, C_L = 10pF, V_1 = -10V, V_8 = +10V$

NOTE:

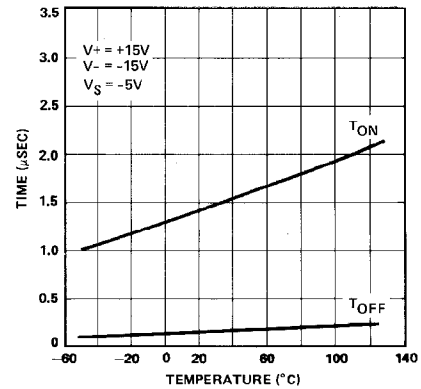
Top Waveforms: Digital Input 5V/Div
Bottom Waveforms: Multiplexer Output (V_D)

TYPICAL PERFORMANCE CHARACTERISTICS (apply to all grades, unless otherwise noted.)

TRANSITION TIME vs TEMPERATURE



ENABLE DELAY TIME vs TEMPERATURE



MUX-16/MUX-28

A.C. TEST CIRCUITS

TRANSITION TIME TEST CIRCUIT

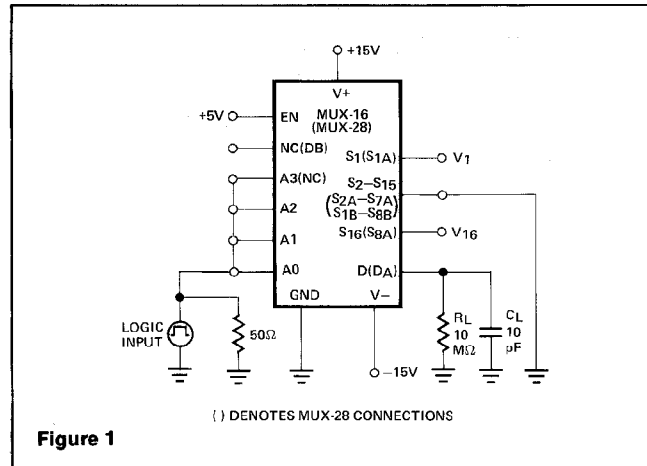


Figure 1

ENABLE DELAY TIME TEST CIRCUIT

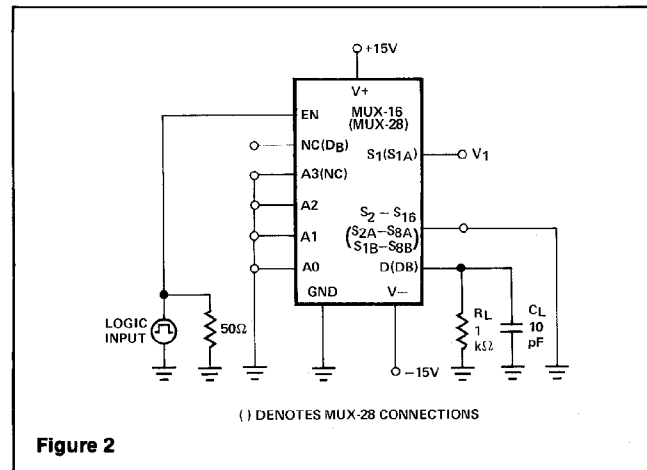


Figure 2

BREAK-BEFORE-MAKE TEST CIRCUIT

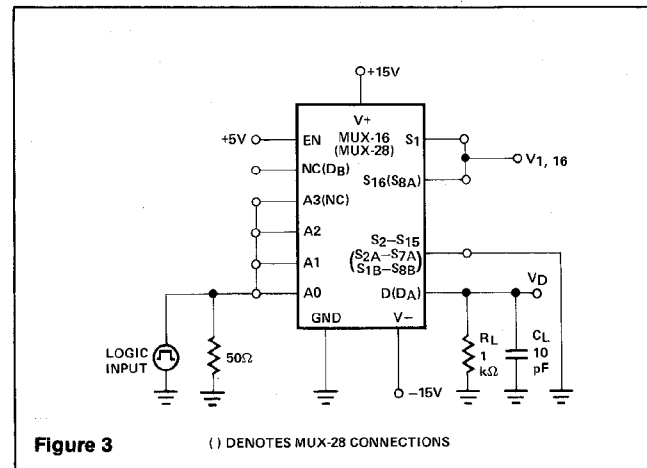
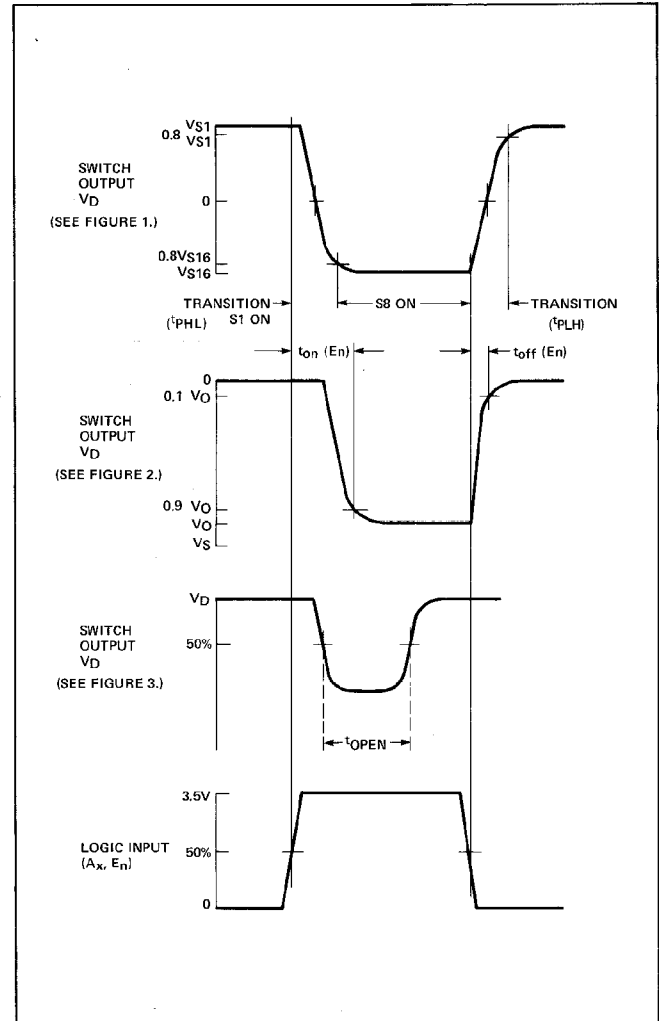


Figure 3

SWITCHING TIME WAVEFORMS



OFF ISOLATION TEST CIRCUIT

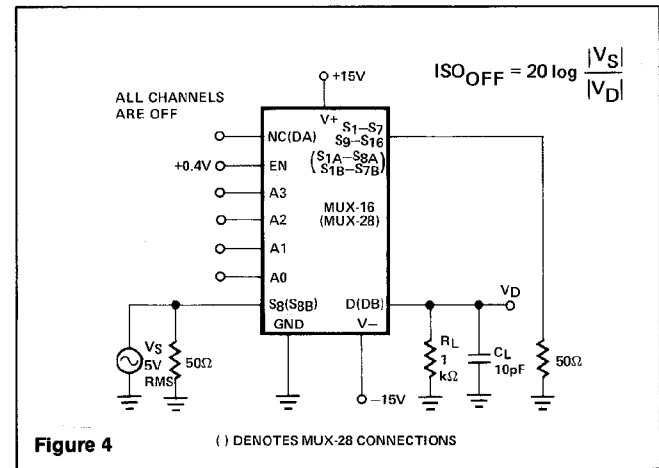


Figure 4

CROSSTALK MEASUREMENT CIRCUIT

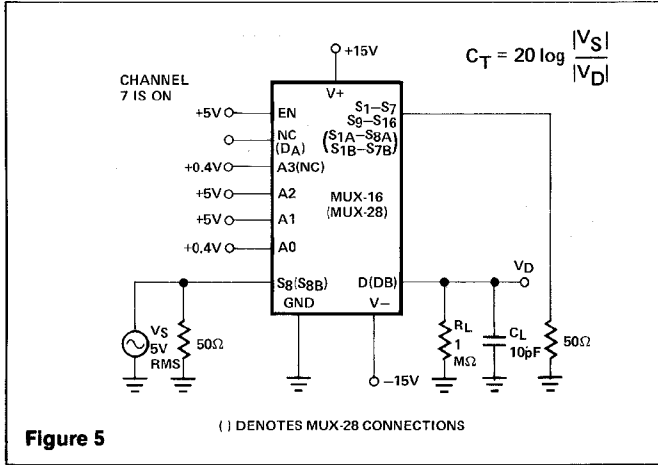
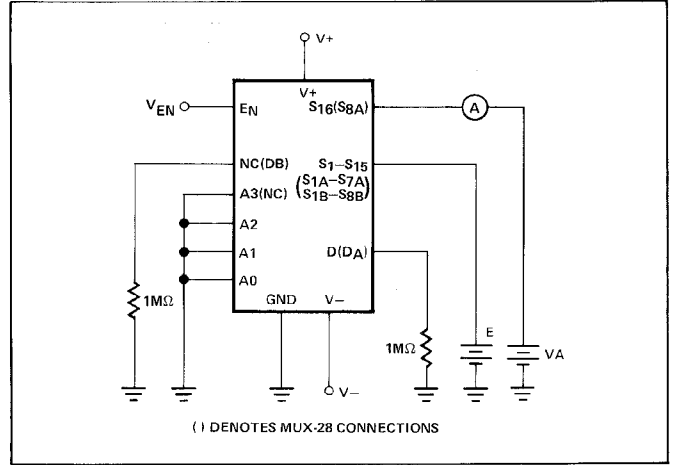


Figure 5

OVERVOLTAGE MEASUREMENT TEST CIRCUIT



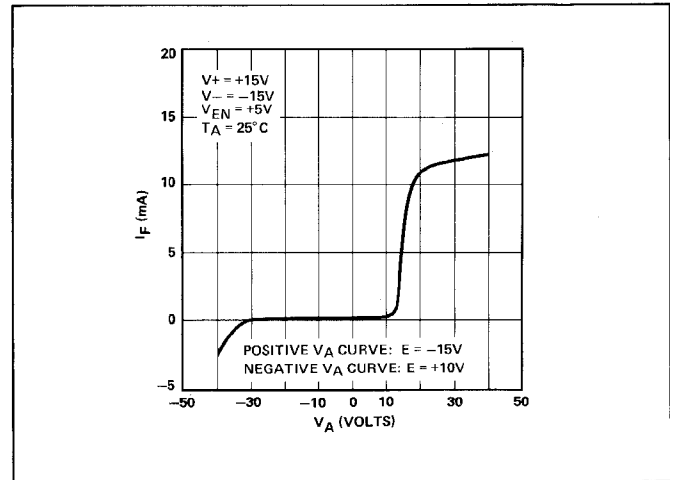
APPLICATIONS INFORMATION

These analog multiplexers employ ion-implanted JFETs in a switch configuration designed to assure break-before-make (B.B.M.) action. The turn-off time is much faster than the turn-on time to guarantee B.B.M. over the full operating temperature and input voltage range. Fabricated with JFET processing rather than CMOS, special handling is not necessary to prevent damage to this multiplexer. Because the digital inputs only require a 2.0V logic "1" input level, power-consuming pullup resistors are not required for TTL compatibility to insure break-before-make switching as is most often the case with CMOS multiplexers. The digital inputs utilize PNP input transistors where input current is maximum at the logic "0" level and drops to that of a reverse-biased diode (about 10nA) as the input voltage is raised above $\approx 1.4V$.

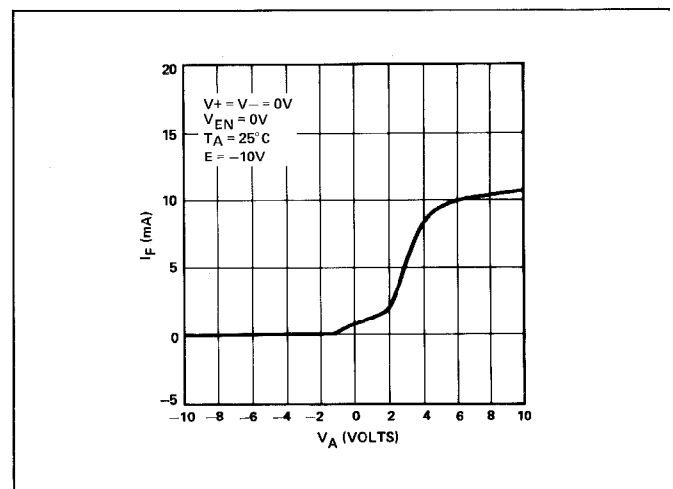
The "ON" resistance, R_{ON} of the analog switches is constant over the wide input voltage range of $-15V$ to $+11V$ with $V_{SUPPLY} = \pm 15V$. The overvoltage and supply-loss V-I characteristics shown indicate typical performance when the multiplexer is subjected to abnormal signals. For normal operation, however, positive input voltages should be restricted to 11V (or 4V less than the positive supply). This assures that the V_{GS} of an OFF FET switch remains greater than its V_p , preventing that channel from being falsely turned ON.

When operating with negative input voltages, the gate-to-channel diode will be turned on if the voltage drop across an ON switch exceeds $-0.6V$. While this condition will cause an error in the output, it will not damage the switch. In lab tests, the multiplexer output has been loaded with a $0.01\mu F$ capacitor in the circuit of Figure 1. With $V_1 = -10V$ and $V_{16} = +10V$, the logic input was driven at a 1kHz rate. The positive-going slew rate was $0.3V/\mu Sec$ which is equivalent to a normal I_{DSS} of 3mA. The negative-going slew rate was $0.7V/\mu sec$ which is equivalent to a "reverse" I_{DSS} of 7mA. Note that when switch one (1) is first turned ON it has a drop of $-20V$ across its terminals. In spite of that fact, the current is limited to approximately twice its normal I_{DSS} .

OVERVOLTAGE V-I CHARACTERISTIC



SUPPLY-LOSS V-I CHARACTERISTIC



MUX-16/MUX-28

SIMPLIFIED SCHEMATIC (MUX-16)

